

NVLAP LAB CODE: 200012-0

IPS Corporation Nagano Calibration Center

Nagano-ken

Japan

is accredited by the National Voluntary Laboratory Accreditation Program for specific services, listed on the Scope of Accreditation, for:

Calibration Laboratories

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communique dated January 2009).

2023-12-13 through 2024-12-31

Effective Dates





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SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

IPS Corporation Nagano Calibration Center	Fields o
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Fields of Calibration Electromagnetics – DC/Low Frequency Time and Frequency Electromagnetics – RF/Microwave

CALIBRATION AND MEASUREMENT CAPABILITIES (CMC) Notes 1,2			
Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
EL	ECTROMAGNETICS -	- DC/LOW FREQUENCY	
AC RESISTANCE and CURRE	NT (20/E02)		
AC Resistance			
Field calibrations available Note 4			
50 Hz to 1 kHz	0.04Ω to 1Ω	5.6 %	LCR Meter
			Oscilloscope, Current Coil,
50 Hz, 60 Hz	0.04Ω to 1Ω	5.1 %	HV Probe
Inductance			
Field calibrations available Note 4			
50 Hz to 1 kHz	Up to 1 H	5.6 %	LCR Meter
50 Hz, 60 Hz	Up to 1 H	5.1 %	Oscilloscope, Current Coil,
			HV Probe
Reactance (X_L)			
Field calibrations available Note 4			
50 Hz to 1 kHz	0.04Ω to 1Ω	5.5 %	LCR Meter
		5.1.0/	Oscilloscope, Current Coil,
50 Hz, 60 Hz	$0.04 \ \Omega$ to $1 \ \Omega$	5.1 %	HV Probe
Consistence			
Capacitance			
Field calibrations available from 4	Lin to 1 uE	5 4 0/	LCD Mater
SU HZ to 1 kHZ	υριοιμε	J.4 %0	LUK Meter

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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
DC RESISTANCE and CURRE	ENT (20/E05)		
Surge Generator			IEC 61000-4-5
Field calibrations available Note 4			
Peak Current, Short circuit			
current waveform			
(rise time/duration: 8/20 µs			
or 5/320 µs)	(0.05 to 3) kA	2.6 %	Oscilloscope
ESD Simulators			IEC 61000 4 2 ISO 10605
Peak current (2 to 30) kV	(6 to 120) A	2 0 %	Oscilloscopa ESD Target
Discharge current	(0 10 150) A	3.9 70	Osemoscope, ESD Target
(30 to 800) ps	(0.2 to 78) A	10%	
(50 10 000) 113	(0.2 to 76) A	4.9 /0	
DC VOLTAGE (20/E06)			
Surge Generator			IEC 61000-4-5
Field calibrations available Note 4			
Peak Voltage, Open circuit			
voltage waveform			
(1.2/50 μs, 10/700 μs)	100 V to 5 kV	2.8 %	Oscilloscope, HV Probe
Overshoot/Undershoot			
Field calibrations available ^{Note 4}			
Voltage	0 mV to 300 V	3.2% + 64 mV	Oscilloscope
		5.2 / 0 / 0 / 11 /	osemescope
EFT/Burst			IEC 61000-4-4
Field calibrations available Note 4			
Peak Voltage	100 V to 6 kV	3.0 %	Oscilloscope, Attenuator
Deals Voltage			
with capacitive clamp		280/	
with capacitive clamp		2.0 70	
Transient Generator			
Field calibrations available Note 4			ISO 7637-2. Annex C
Peak Voltage	(10 to 600) V	4.1 %	ISO-7637-3
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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
DC Voltage - Measure Field calibrations available Note 4	0.01 V to 1000 V	0.11 %	DMM
ESD Simulators DC High Voltage	0.5 kV to 1 kV 1 kV to 3 kV 3 kV to 40 kV	2.3 % 1.2 % 1.1 %	IEC 61000-4-2, ISO 10605 DHM-40/10
LF AC VOLTAGE (20/E09)		1	
AC Voltage - Measure Field calibrations available Note 4 0.1 V to 750 V	3 Hz to 5 Hz 5 Hz to 10 Hz 10 Hz to 20 kHz 20 kHz to 50 kHz	3.1 % 0.46 % 0.12 % 0.18 %	DMM
	50 kHz to 100 kHz	0.79 %	
	100 kHz to 300 kHz	5.2 %	
10 mV to 5 V	DC to 100 MHz	3.3 %	Oscilloscope
5 V to 4 kV	DC to 50 MHz	3.8 %	Oscilloscope, HV Probe
Voltage Dip Simulator Field calibrations available Note 4 AC Voltage – (50 to 60) Hz	10 V to 500 V	0.4 %	DMM
MAGNETICS (20/E13)			•
Magnetic Field Generator Note 4 50 Hz or 60 Hz Coil Current	1 A to 100 A 0.1 A to 1 A	1.0 % 1.3 %	IEC 61000-4-8
Coil Factor (I \geq 1A) (I < 1 A)	0.10 to 20	2.4 % 2.5 %	

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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
	TIME and FI	REQUENCY	
FREQUENCY DISSEMINATIO	DN (20/F01)		
EFT/Burst (100 V to 6 kV) Field calibrations available Note 4			IEC 61000-4-4 Oscilloscope, Attenuator
Repetition frequency	1 kHz to 500 kHz	0.6 %	_
Burst duration	0.5 ms to 20 ms	0.6 %	
Burst period	100 ms to 500 ms	0.4 %	
Voltage Dip Simulator Field calibrations available ^{Note 4}			
Duration Time	10 ms to 5 s	2.4 %	Oscilloscope
Frequency - Measure	1 Hz to 1 GHz	0.5 %	Oscilloscope
Field calibrations available Note 4	(45 to 65) Hz	0.1 %	DMM
Differential - Time Measure Field calibrations available Note 4	1 ns to 5 s	0.6 %	Oscilloscope
Differential - Phase Field calibrations available ^{Note 4}	0° to 360°	2.5°	Oscilloscope
PULSE WAVEFORM (20/F04)			
ESD Simulators (2 kV to 30 kV) Rise time	0.6 ns to 1 ns	6.9 %	IEC 61000-4-2, ISO 10605 (Excluding RC time constant) Oscilloscope
EFT/Burst (100 V to 6 kV) Field calibrations available Note 4 Without Capacitive Clamp			IEC 61000-4-4 Oscilloscope, Attenuator
Rise time	1 ns to 10 ns	1.5 %	
Impulse duration With Capacitive Clamp	10 ns to 500 ns	1.0 %	
Rise time	1 ns to 10 ns	1.4 %	
Impulse duration	10 ns to 500 ns	0.6 %	
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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
Surge Generator			IEC 61000-4-5
Field calibrations available Note 4			
Open-circuit voltage waveform			
(100 V to 5 kV)			
(Rise time/duration: 1.2/50 µs or			
10/700 μs)			
Rise Time	0.5 µs to 20 µs	3.5 %	Oscilloscope, HV Probe
Half value duration	10 µs to 1000 µs	3.7 %	_
Short-circuit current waveform			
(50 A to 2 kA)			
(Rise time/duration: 8/20 µs or			
5/320 μs)			
Rise Time	1 μs to 20 μs	3.4 %	
Half value duration	10 µs to 500 µs	2.3 %	
Transient Generator			ISO 7637-2, Annex C
(10 V to 600 V)			
Field calibrations available Note 4			ISO 7637-3
Rise Time	1 ns to 50 ms	5.8 %	Oscilloscope
Pulse Width	50 ns to 3 s	5.9 %	
Voltage Dip Simulator			
(10 V to 500 V; 50 Hz or 60 Hz)			IEC 61000-4-11
Field calibrations available Note 4			IEC 61000-4-34
Rise/Fall Time	1 μs to 5 μs	2.7 %	Oscilloscope
	ELECIKUWIAGNETIC	S – KF/MICKUWAVE	
MICKOWAVE ANTENNA PAR	(AMETERS (20/R08)		Substitution mathed
Gruch as the HA0102/UHA0105)	$20 \text{ MHz} t_{2} 80 \text{ MHz}$	0.6.4D	Substitution method
(such as the HA9105/OHA9105)		0.0 dB	Notres als Ameleran
(D = 10 m H = 2 m)	(1 uned at 80 MHz)	0.6.4D	Network Analyzer
(D - 10 m, H = 2 m)	30 MHz to 1 GHz		
		0.0 uD	
	1		1

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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
Biconical Antenna,			Substitution method
Antenna Factor			
Horizontal ($D = 10 \text{ m}, H = 2 \text{ m}$)	30 MHz to 300 MHz	0.7 dB	Network Analyzer
Horizontal ($D = 3 m, H = 2 m$)		0.6 dB	
Horizontal ($D = 3 m, H = 1 m$)		0.7 dB	
Vertical ($D = 3 m$, $H = 1.5 m$)		0.8 dB	
Vertical ($D = 3 m, H = 1 m$)		0.9 dB	
Log-Periodic Antenna Antenna Factor			Substitution method
Horizontal ($D = 10 \text{ m}, H = 2 \text{ m}$)	200 MHz to 1 GHz	1.1 dB	Network Analyzer
Horizontal ($D = 3 m, H = 2 m$)		1.1 dB	
Horizontal ($D = 3 m, H = 1 m$)		1.1 dB	
Vertical ($D = 3 \text{ m}, H = 1.5 \text{ m}$)		1.1 dB	
Vertical (D = 3 m , H = 1 m)		1.2 dB	
Bi-log Antenna			Substitution method
Horizontal Antenna Factor	30 MHz to 1 GHz		
(D = 10 m, H = 2 m)		1.3 dB	Network Analyzer
(D = 3 m, H = 2 m)		1.3 dB	
Biconical Antenna			SAE ARP958
Antenna Factor	25 MHz to 300 MHz		Network Analyzer
Horizontal ($D = 1 m, H = 3 m$)		0.9 dB	
Vertical ($D = 1 m, H = 3 m$)		0.8 dB	
Log-Periodic Antenna			SAE ARP958
Antenna Factor			
Horizontal ($D = 1 m, H = 3 m$)	150 MHz to 300 MHz	0.8 dB	Network Analyzer
Horizontal ($D = 1 m, H = 3 m$)	300 MHz to 1 GHz	0.5 dB	
Horizontal ($D = 1 m, H = 3 m$)	1 GHz to 1.8 GHz	0.7 dB	
Vertical ($D = 1 m, H = 3 m$)	150 MHz to 300 MHz	0.6 dB	
Vertical ($D = 1 m, H = 3 m$)	300 MHz to 1 GHz	0.5 dB	
Vertical ($D = 1 m, H = 3 m$)	1 GHz to 1.8 GHz	0.6 dB	
	1		

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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
Horn Antenna Antenna Factor Free Space (D = 1 m, H = 3 m)	0.75 GHz to 18 GHz 0.75 GHz to 18 GHz	1.0 dB 1.4 dB	SAE ARP958 Network Analyzer Spectrum Analyzer
NSA Measurement Field calibrations available ^{Note 4} Horizontal Vertical Horizontal Vertical	30 MHz to 200 MHz 200 MHz to 1 GHz	1.4 dB 1.7 dB 1.4 dB 1.5 dB	CISPR 16-1-4, and ANSI C63.4 Network Analyzer
SVSWR Measurement Field calibrations available ^{Note 4} Horizontal Vertical Horizontal Vertical Horizontal Vertical Horizontal Vertical	1 GHz to 3 GHz 3 GHz to 6 GHz 6 GHz to 12 GHz 12 GHz to 18 GHz	2.2 dB 2.1 dB 2.4 dB 2.7 dB 2.5 dB 1.9 dB 2.0 dB 1.9 dB	CISPR 16-1-4, and ANSI C63.4 Network Analyzer Spectrum Analyzer
Absorbing Clamp Clamp Factor Decoupling Factor (DF) Decoupling Factor (DR)	30 MHz to 300 MHz 300 MHz to 1 GHz 30 MHz to 150 MHz 150 MHz to 1 GHz 30 MHz to 150 MHz 150 MHz to 1 GHz	0.8 dB 1.1 dB 1.3 dB 4.4 dB 0.9 dB 6.1 dB	CISPR 16-1-3 Original Method Network Analyzer
Biconical, Log-periodic, Hybrid Antenna Horizontal Antenna Factor (D = 10 m, H = 2 m)	30 MHz to 300 MHz 300 MHz to 1 GHz	1.1 dB 0.9 dB	Standard Site Method ANSI C63.5 , CISPR 16-1-6 (OATS Calibration)

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Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
Horizontal Antenna Factor	30 MHz to 300 MHz	1.3 dB	
(D = 10 m, H = 1 m)	300 MHz to 1 GHz	1.1 dB	
Vertical Antenna Factor	30 MHz to 300 MHz	1.4 dB	
(D = 10 m, H = 1 m)	300 MHz to 1 GHz	1.5 dB	
Vertical Antenna Factor	30 MHz to 300 MHz	1.3 dB	
(D = 10 m, H = 1.5 m)	300 MHz to 1 GHz	1.2 dB	
Horizontal Antenna Factor	30 MHz to 300 MHz	1.1.dB	
(D = 3 m H = 2 m)	300 MHz to 1 GHz	1.0 dB	
Horizontal Antenna Factor	30 MHz to 300 MHz	1.3 dB	
(D = 3 m, H = 1 m)	300 MHz to 1 GHz	1.1 dB	
Vertical Antenna Factor	30 MHz to 300 MHz	1.3 dB	
(D = 3 m, H = 1 m)	300 MHz to 1 GHz	1.5 dB	
Vertical Antenna Factor	30 MHz to 300 MHz	1.2 dB	
(D = 3 m, H = 1.5 m)	300 MHz to 1 GHz	1.2 dB	
Horizontal GSCF	30 MHz to 300 MHz	1.3 dB	
(D = 10 m, H = 1 m)	300 MHz to 1 GHz	1.1 dB	
Vertical GSCF	30 MHz to 300 MHz	1.6 dB	
(D = 10 m, H = 1 m)	300 MHz to 1 GHz	1.4 dB	
Vertical GSCF	30 MHz to 300 MHz	1.7 dB	
(D = 10 m, H = 1.5 m)	300 MHz to 1 GHz	1.2 dB	
Horizontal GSCF	30 MHz to 300 MHz	1.2 dB	
(D = 3 m, H = 2 m)	300 MHz to 1 GHz	0.9 dB	
Horizontal GSCF	30 MHz to 300 MHz	1.4 dB	
(D = 3 m, H = 1 m)	300 MHz to 1 GHz	1.2 dB	
Vertical GSCF	30 MHz to 300 MHz	1.5 dB	
(D = 3 m, H = 1 m)	300 MHz to 1 GHz	1.5 dB	
Vertical GSCF	30 MHz to 300 MHz	1.6 dB	
(D = 3 m, H = 1.5 m)	300 MHz to 1 GHz	1.2 dB	
Biconical Log-periodic Hybrid			ANSI C63 5
Antenna			(OATS Calibration)
Antenna Symmetry	20 MHz to 300 MHz	0.6 dB	
	300 MHz to 1 GHz	0.6 dB	
	1 GHz to 1.8 GHz	0.5 dB	

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Measured Parameter or		Expanded	
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
Horn Antenna, Log Periodic			Standard Site Method
Free Space Antenna Factor			ANSI C63.5 , CISPR 16-1-6
(D = 3 m)	0.75 GHz to 18 GHz	1.0 dB	Network Analyzer
	0.75 GHz to 18 GHz	1.2 dB	Spectrum Analyzer
		1.0.15	
Loop Antenna – Antenna Factor	9 kHz to 30 MHz	1.2 dB	Standard Field Strength
Tanas Taan Antonna			Method
Large Loop Antenna – Validation Easter	0 kHz to 20 MHz	0.8 4D	CISDD 16 1 4 Annov C
Field calibrations available ^{Note 4}	9 KHZ 10 50 WIHZ	0.8 dB	CISFR 10-1-4 Annex C
Theid calibrations available			
SCATTERING PARAMETERS	(20/R18)		
Impedance & VSWR - Measure			Network Analyzer
Field calibrations available Note 4			
0 to 0.5 (Linear)	9 kHz to 300 kHz	2.0 % + 0.002	
	300 kHz to 10 MHz	2.0 % + 0.002	
	10 MHz to 3 GHz	2.4 % + 0.002	
	3 GHz to 6 GHz	3.5 % + 0.002	
	6 GHz to 18 GHz	7.1 % + 0.002	
	18 GHz to 20 GHz	8.4 % + 0.006	
		2 7 8/ 1 0 002	
0.5 to 1 (Linear)	9 kHz to 300 kHz	3.7% + 0.002	
	300 KHZ to 10 MHZ	3.7% + 0.002	
	10 MHZ to 3 GHZ	4.3 % + 0.002	
		0.8 % + 0.002	
	18 GHz to $18 GHz$	15.5% + 0.002 16.2.% + 0.006	
		$10.2 70 \pm 0.000$	
Directional Coupler			
(9 kHz to 6 GHz)			
Field calibrations available Note 4			
Insertion Loss	0 dB to 60 dB	0.20 dB	Network Analyzer
Coupling Factor	0 dB to 60 dB	0.20 dB	
1 0			

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Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks
EM Clamp / Decoupling Clamp 0.1 MHz to 230 MHz Field calibrations available ^{Note 4}			IEC 61000-4-6
Insertion Loss	100 kHz to 230 MHz	0.4 dB	
Impedance	100 kHz to 100 MHz 100 MHz to 230 MHz	6.0 % 8.8 %	
Decoupling Factor	100 kHz to 100 MHz 100 MHz to 230 MHz	0.6 dB 0.7 dB	
Coupling Factor	100 kHz to 100 MHz 100 MHz to 230 MHz	0.7 dB 0.6 dB	
50 ohm to 150 ohm Adaptor 0.1 MHz to 230 MHz Field calibrations available Note 4 Insertion Loss	0 dB to 60 dB	0.3 dB	Network Analyzer
Current Probe/Current Injection Probe 10 kHz to 500 MHz Field calibrations available ^{Note 4} Insertion Loss Transfer Impedance	0 dB to 60 dB 0 dBΩ to 60 dBΩ	0.5 dB 0.5 dB	
Calibration Jig of Current Injection Probe Field calibrations available Note 4 Transmission Loss	150 kHz to 230 MHz	0.6 dB	IEC 61000-4-6
Hi-Impedance Probe 9 kHz to 30 MHz Field calibrations available ^{Note 4} Voltage Division Factor (VDF)	0 dB to 60 dB	0.3 dB	

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Measured Parameter or		Expanded		
Device Calibrated	Range	Uncertainty Notes 3, 5	Remarks	
RF Insertion Loss/Gain Measure				
Field calibrations available Note 4				
9 kHz to 300 kHz	0 dB to 60 dB	0.30 dB		
300 kHz to 10 MHz		0.25 dB		
10 MHz to 3 GHz		0.18 dB		
3 GHz to 6 GHz		0.24 dB		
6 GHz to 18 GHz		0.34 dB		
18 GHz to 20 GHz		0.41 dB		
LISN			CISPR 16-1-2 CISPR 25	
Field calibrations available ^{Note 4}			ISO 7637-1 and -2	
Insertion Loss/VDF	9 kHz to 108 MHz	0.18 dB	ANSI C63 4	
		0.10 0.2		
Impedance	9 kHz to 100 kHz	5.1 %		
-	100 kHz to 108 MHz	1.1 %		
Phase	0 kHz to 30 MHz	1 00		
Thase	30 MHz to 108 MHz	-1.9 6.6°		
	50 WILL 10 100 WILL	0.0		
Isolation	9 kHz to 108 MHz	2.9 dB		
CDN				
Field calibrations available ^{Note 4}				
Insertion Loss				
(-30 to 10) dB	100 kHz to 230 MHz	0.1 dB		
Impedance	100 KHZ to 250 WHZ	0.1 aD		
(90 to 210) Ω	100 kHz to 80 MHz	4.2 %		
() 0 00 210)	80 MHz to 230 MHz	9.2 %		
CMAD				
Field calibrations available Note 4				
Transmission Coefficient	30 MHz to 200 MHz	0.0051 (linear)		
Reflection Coefficient	30 MHz to 200 MHz	0.013 (linear)		
END				

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Notes

Note 1: A Calibration and Measurement Capability (CMC) is a description of the best result of a calibration or measurement (result with the smallest uncertainty of measurement) that is available to the laboratory's customers under normal conditions, when performing more or less routine calibrations of nearly ideal measurement standards or instruments. The CMC is described in the laboratory's scope of accreditation by: the measurement parameter/device being calibrated, the measurement range, the uncertainty associated with that range (see note 3), and remarks on additional parameters, if applicable.

Note 2: Calibration and Measurement Capabilities are traceable to the national measurement standards of the U.S. or to the national measurement standards of other countries and are thus traceable to the internationally accepted representation of the appropriate SI (Système International) unit.

Note 3: The uncertainty associated with a measurement in a CMC is an expanded uncertainty with a level of confidence of approximately 95 %, typically using a coverage factor of k = 2. However, laboratories may report a coverage factor different than k = 2 to achieve the 95 % level of confidence. Units for the measurand and its uncertainty are to match. Exceptions to this occur when marketplace practice employs mixed units, such as when the artifact to be measured is labeled in non-SI units and the uncertainty is given in SI units (Example: 5 lb weight with uncertainty given in mg).

Note 3a: The uncertainty of a specific calibration by the laboratory may be greater than the uncertainty in the CMC due to the condition and behavior of the customer's device and specific circumstances of the calibration. The uncertainties quoted do not include possible effects on the calibrated device of transportation, long term stability, or intended use. **Note 3b:** As the CMC represents the best measurement results achievable under normal conditions, the accredited calibration laboratory shall not report smaller uncertainty of measurement than that given in a CMC for calibrations or measurements

covered by that CMC.

Note 3c: As described in Note 1, CMCs cover calibrations and measurements that are available to the laboratory's customers under *normal conditions*. However, the laboratory may have the capability to offer special tests, employing special conditions, which yield calibration or measurement results with lower uncertainties. Such special tests are not covered by the CMCs and are outside the laboratory's scope of accreditation. In this case, NVLAP requirements for the labeling, on calibration reports, of results outside the laboratory's scope of accreditation apply. These requirements are set out in Annex A.1.h. of NIST Handbook 150, Procedures and General Requirements.

Note 4: Uncertainties associated with field service calibration may be greater as they incorporate on-site environmental contributions, transportation effects, or other factors that affect the measurements. (This note applies only if marked in the body of the scope.)

Note 5: Values listed with percent (%) are percent of reading or generated value unless otherwise noted.

Note 6: NVLAP accreditation is the formal recognition of specific calibration capabilities. Neither NVLAP nor NIST guarantee the accuracy of individual calibrations made by accredited laboratories.

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